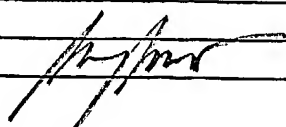


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	11-177	10/634,844
	APPLICANT Hideyuki HAYAKAWA et al.	
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U.S. PATENT DOCUMENTS						
Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date
	W	4,898,258	2/6/90	Ohe et al. (corres. to JP1-218975)		
	W	5,785,145	7/28/98	Wakao et al. (corres. to JP8-192757)		
	W	5,810,111	9/22/98	Takeuchi et al. (corres. to JP8-258730, EP0733536)		
	W	5,836,419	11/17/98	Shimizu et al. (corres. to JP8-175403)		
	W	5,844,386	12/1/98	Matsuoka et al. (corres. to JP9-24847, EP0753448)		
	W	6,078,155	6/20/00	Tominaga et al. (corres. to JP2000-203437)		
	W	6,107,716	8/22/00	Penketh (corres. to JP2001-506558, WO98/26972)		
	W	6,123,167	9/26/00	Miller et al. (corres. to JP2000-6826, EP0963900)		
	W	2002/0060105 A1	5/23/02	Tominaga et al. (corres. to JP2002-120739)		

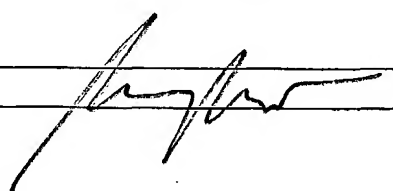
FOREIGN PATENT DOCUMENTS							
Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation	
						Yes	No
	W	WO 98/26972	6/25/98	PCT Penketh			
	W	0733536	9/25/96	EP Takeuchi et al.			
	W	0753448	1/15/97	EP Matsuoka et al.			
	W	0963900	12/15/99	EP Miller et al.			
	W	64-6178	1/13/89	Japan Ohe et al.		X	
	W	1-218975	9/1/89	Japan Ohe et al.			
	W	1-154073	10/24/89	Japan Suda et al.		X	
	W	6-281513	10/7/94	Japan Sonoda		X	
	W	8-159887	6/21/96	Japan Shinohara		X	
	W	8-164861	6/25/96	Japan Chikuma et al.		X	

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	APPLICANT Hideyuki HAYAKAWA et al.	
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	8/6/2008	

FOREIGN PATENT DOCUMENTS							
Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation	
						Yes	No
	TW	8-175403	7/9/96	Japan Shimizu et al.		X	
	TW	8-188164	7/23/96	Japan Endo et al.		page 1 in the spec.	
	TW	8-192757	7/30/96	Japan Wakao et al.			
	TW	8-258730	10/8/96	Japan Takeuchi et al.			
	TW	9-24847	1/28/97	Japan Matsuoka et al.			
	TW	2000-6826	1/11/00	Japan Miller			
	TW	2000-203437	7/25/00	Japan Tominaga et al.			
	TW	2000-313345	11/14/00	Japan Ueno et al.		X	
	TW	2000-318628	11/21/00	Japan Takashita		X	
	TW	2001-16817	1/19/01	Japan Ishikawa		X	
	TW	2001-112209	4/20/01	Japan Yamamoto		X	
		2001-506558	5/22/01	Japan Penketh	msy		
	TW	2002-120739	4/23/02	Japan Tominaga et al.			

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